

<b>Notice of References Cited</b>	Application/Control No. 10/605,308	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-5,053,849	10-1991	Izawa et al.	257/401
	C	US-5,061,647	10-1991	Roth et al.	438/304
	D	US-5,368,686 A	11-1994	Tatsumi et al.	438/696
	E	US-5,374,575 A	12-1994	Kim et al.	438/291
	F	US-5,502,336 A	03-1996	Park et al.	257/754
	G	US-5,986,305 A	11-1999	Wu, Shye-Lin	257/344
	H	US-5,994,192 A	11-1999	Chen, Chun-Yao	438/303
	I	US-6,001,719 A	12-1999	Cho et al.	438/592
	J	US-6,180,474 B1	01-2001	Kim, Hong-Seog	438/304
	K	US-6,235,621 B1	05-2001	Jeng et al.	438/592
	L	US-6,245,620 B1	06-2001	Jang et al.	438/303
	M	US-6,342,450 B1	01-2002	Lattard, Edith	438/696

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
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**NON-PATENT DOCUMENTS**

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,437,411 B1	08-2002	Choi et al.	257/413
	B	US-6,660,581 B1	12-2003	Yang et al.	438/242
	C	US-6,674,139 B2	01-2004	Mandelman et al.	257/412
	D	US-6,723,623 B1	04-2004	Nguyen, Phong N.	438/525
	E	US-6,730,552 B1	05-2004	Abadeer et al.	438/197
	F	US-6,740,550 B2	05-2004	Choi et al.	438/199
	G	US-6,878,613 B2	04-2005	Stottko et al.	438/592
	H	US-6,885,052 B2	04-2005	Ahn et al.	257/296
	I	US-2001/0046737	11-2001	Ahn et al.	438/253
	J	US-2002/0072156 A1	06-2002	Lee et al.	438/151
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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